IN THE SPECIFICATION

Please replace the Title of the Invention with the following new title:

--SPRING CONTACT PROBE DEVICE FOR ELECTRICAL TESTING--.

Please replace the paragraph beginning on page 4, line 28, with the following:

--FIG. 1 is an isometric view of a spring probe 10 according to a preferred embodiment of the invention. It comprises a unitary body comprising a resilient spring section 12, a plunger section 16 extending from a distal end 61 of the resilient spring section 12 for contacting a semiconductor device under test and a stopper 20 projecting from the plunger section 16 substantially transversely to an axial direction of the plunger section 16. The probe 10 may be formed from a wire-like material. Generally, the wire-like material has a form akin to a flexible metallic thread or slender rod.--.

Please replace the paragraph beginning on page 5, line 4, with the following:

--The spring probe 10 has a second plunger section 14 at ~~another distal~~ a proximal end 62 of the spring section 12 that is opposite to the plunger section 16. The second plunger section 14 extends out of the spring section 12 in a substantially straight line in the same general axial direction as the spring section 12. It is preferable for the second plunger section 14 to extend substantially parallel to the plunger section 16 when the spring section 12 is uncompressed. Also, it is advantageous for the second plunger section 14 and the plunger section 16 to lie on opposite sides of an axial plane passing perpendicularly through a center 13 of the spring section 12. This allows the plunger sections 16 of two opposing spring probes 10 to contact points that closer together when they are arranged next to each other as mirror images of each other. Generally, the plunger sections 14, 16 are aligned asymmetrically about an axis of rotation when the plunger sections 14, 16 are biased and the spring section 12 is uncompressed.--.

Please replace the paragraph beginning on page 8, line 13, with the following:

--FIG. 4 is an isometric view of a manual test jig 32 [[36]] including the test contactor 22 of FIG. 2. FIG. 5 gives a partial cross-sectional view of the manual test jig 32 [[36]] of FIG. 4. The manual test jig 32 [[36]] consists of the test contactor 22 attached to a base plate 46 through four guide rods 44 and two compression springs 42. A package holder 54 for holding the DUT 52 is securely fastened on top of the bottom plate 50. The test contactor 22 may be lowered to make contact with the DUT 52 by pressing it downward and then by securing it with the stainless steel knob fastener 33. Once secured, the test contactor 22 may be lowered further by turning the stainless steel knob fastener 33 until the spring probes 10 are compressed against the electrical contacts of the DUT 52. Testing can then take place by running a test program.--.